Notice of References Cited Application/Control No. 10/702,429 Examiner John T. Kwon Applicant(s)/Patent Under Reexamination YASUI ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,568,177	05-2003	Surnilla, Gopichandra	60/285
	В	US-6,564,543	05-2003	Orzel et al.	60/277
	С	US-6,539,704	04-2003	Surnilla et al.	60/274
	D	US-6,370,935	04-2002	He et al.	73/1.34
	Е	US-6,308,697	10-2001	Surnilla et al.	123/672
	F	US-5,758,494	06-1998	Davey, Christopher Kirk	60/274
	G	US-5,365,216	11-1994	Kotwicki et al.	340/439
	Н	US-5,363,091	11-1994	Kotwicki et al.	340/439
	ı	US-5,325,711	07-1994	Hamburg et al.	73/118.1
	· J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
	v		
	w		
	х	A being forcided with this Office series (See MDED 9 707 05(s).)	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.